

P54/74FCT39520C/D — P54/74FCT39521C/D

PIPELINE REGISTERS

FEATURES

- Function and Drive Compatible with the Fastest TTL Logic
- Inputs and Outputs Interface with TTL Logic Levels
- $3.3V \pm 0.2V$ Power Supply CMOS for Lowest Power Dissipation
- FCT3-D speed at 5.1ns max. (Com'I)
- FCT3-C speed at 6.0ns max. (Com'I)
- Fully TTL Compatible Input and Output Logic Levels
- Edge-rate Control Circuitry for Significantly Improved Noise Characteristics
- ESD Protection Exceeds 2000V
- 48mA Sink Current (Com'I), 32mA (MII)
- 15mA Source Current (Com'I), 12mA (MII)
- Multiple Center Power and Ground Pins
- $t_{po} = 4.8$ ns Over Commercial Temperature and V_{cc} Range
- Single and Dual Pipeline Operation Modes
- Multiplexed Data Inputs and Outputs
- Manufactured In 0.4 micron PACE Technology™

DESCRIPTION

The 'FCT39520 and 'FCT39521 are multi-level 8-bit wide pipeline registers. Each device consists of 4 registers A1, A2, B1 and B2 which are configured by the instruction inputs I_0 , I_1 as a single 4-level pipeline or as two 2-level pipelines. The contents of any register may be read at the multiplexed output at any time by using the mux-selection controls S_0 and S_1 .

The pipeline registers are positive edge triggered and data is shifted by the rising edge of the clock input. Instruction $I = 0$ selects the 4-level pipeline mode. Instruction $I = 1$ selects the 2-level B pipeline while $I = 2$ selects the 2-level A pipeline. $I = 3$ is the HOLD instruction; no shifting is performed by the clock in this mode.

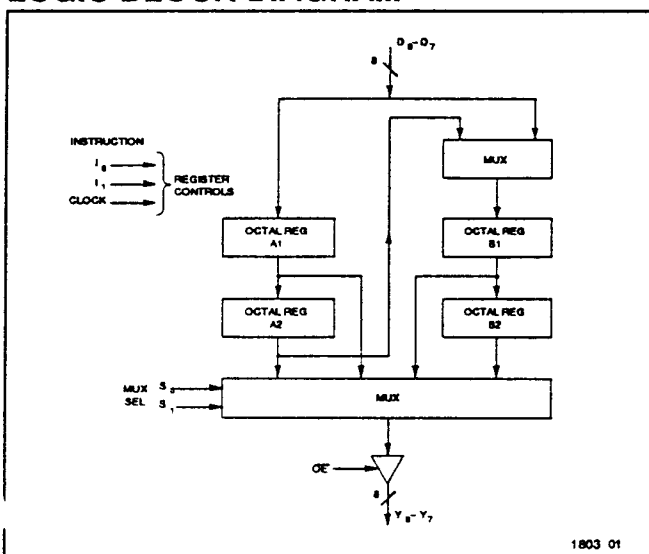
The 'FCT39520 and 'FCT39521 differ only in the 2-level operation mode. For the 'FCT39520, data is shifted from level 1 to level 2 and new data is loaded into level 1. In the

'FCT39521, new data is overwritten into level 1. To shift data from level 1 to level 2 in the 'FCT39521, the 4-level pipeline mode must be used. Note that new data will also be clocked into both A1 and B1 during this 4-level shift operation.

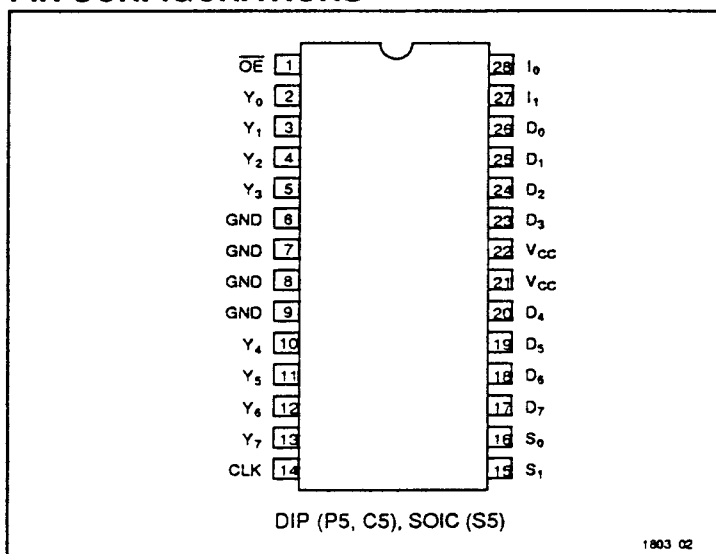
The 'FCT39520 and 'FCT39521 are manufactured with PACE III Technology™ which is Performance Advanced CMOS Engineered with two-level metal and epitaxial substrates to use 0.4 micron effective channel lengths giving 250 picoseconds loaded* internal gate delays. The nominal supply voltage is reduced from the conventional 5.0V to 3.3V, thus reducing output swings dramatically. This, together with the (lower inductance) center power and ground pins, significantly reduces noise and ground bounce that would otherwise occur for very high speed circuitry.

*For a fan-in/fan-out of 4, at 85°C junction temperature and 3.3V supply.

LOGIC BLOCK DIAGRAM



PIN CONFIGURATIONS



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ABSOLUTE MAXIMUM RATINGS^{1,2}

Symbol	Parameter	Value	Unit
T_{STG}	Storage Temperature	-65 to +150	°C
T_A	Ambient Temperature Under Bias	-65 to +135	°C
V_{CC}	V_{CC} Potential to Ground	-0.5 to +5.0	V
I_{IN}	Input Current	-30 to +5.0	mA

Notes:

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1. Operation beyond the limits set forth in the above table may impair the useful life of the device. Unless otherwise noted, these limits are over the operating free-air temperature range.

RECOMMENDED OPERATING CONDITIONS

Free Air Ambient Temperature	Min	Max
Military	-55°C	+125°C
Commercial	0°C	+70°C

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Symbol	Parameter	Value	Unit
I_{OUTPUT}	Current Applied to Output	120	mA
V_{IN}	Input Voltage	-0.5 to $V_{CC} + 0.5$	V
V_{OUT}	Voltage Applied to Output	-0.5 to $V_{CC} + 0.5$	V

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2. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground.

Supply Voltage (V_{CC})	Min	Max
Military	+3.1V	+3.5V
Commercial		

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DC ELECTRICAL CHARACTERISTICS (Over recommended operating conditions)

Symbol	Parameter		Min	Typ ¹	Max	Units	V_{CC}	Conditions
V_{IH}	Input HIGH Voltage		2.0		$V_{CC} + 0.5$	V		
V_{IL}	Input LOW Voltage		-0.5		0.8	V		
V_H	Hysteresis			0.35		V		All inputs
V_{IK}	Input Clamp Diode Voltage			-0.7	-1.2	V	MIN	$I_{IN} = -18\text{mA}$
V_{OH}	Output HIGH Voltage	Military/Commercial (CMOS)	$V_{CC} - 0.2$	V_{CC}		V	MIN	$I_{OH} = -300\mu\text{A}$
		Military (TTL)	2.4			V	MIN	$I_{OH} = -12\text{mA}$
		Commercial (TTL)	2.4			V	MIN	$I_{OH} = -15\text{mA}$
V_{OL}	Output LOW Voltage	Military/Commercial (CMOS)		GND	0.2	V	MIN	$I_{OL} = 300\mu\text{A}$
		Military (TTL)		0.3	0.5	V	MIN	$I_{OL} = 32\text{mA}$
		Commercial (TTL)		0.3	0.5	V	MIN	$I_{OL} = 48\text{mA}$
I_{IH}	Input HIGH Current				5	μA	MAX	$V_{IN} = V_{CC}$
I_{IL}	Input LOW Current				-5	μA	MAX	$V_{IN} = \text{GND}$
I_{IH}	Input HIGH Current				5	μA	MAX	$V_{IN} = 2.7\text{V}$
I_{IL}	Input LOW Current				-5	μA	MAX	$V_{IN} = 0.5\text{V}$
I_{OZH}	Off State I_{OUT} HIGH-Level Output Current				10	μA	MAX	$V_{OUT} = V_{CC}$
I_{OZL}	Off State I_{OUT} LOW-Level Output Current				-10	μA	MAX	$V_{OUT} = \text{GND}$
I_{OZH}	Off State I_{OUT} HIGH-Level Output Current				10	μA	MAX	$V_{OUT} = 2.7\text{V}$
I_{OZL}	Off State I_{OUT} LOW-Level Output Current				-10	μA	MAX	$V_{OUT} = 0.5\text{V}$
I_{OS}	Output Short Circuit Current ²		-60	-120	-225	mA	MAX	$V_{OUT} = 0.0\text{V}$
C_{IN}	Input Capacitance ³			5	10	pF	MAX	All inputs
C_{OUT}	Output Capacitance ³			9	12	pF	MAX	All outputs

Notes:

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- Typical limits are at $V_{CC} = 3.3\text{V}$, $T_A = +25^\circ\text{C}$ ambient.
- Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect

operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

- This parameter is guaranteed but not tested.

DC CHARACTERISTICS (Over recommended operating conditions unless otherwise specified.)

Symbol	Parameter	Typ ¹	Max	Units	Conditions
I_{CC}	Quiescent Power Supply Current (CMOS inputs)	0.003	0.5	mA	$V_{CC} = \text{MAX}$, $f_1 = 0$, Outputs Open, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
ΔI_{CC}	Quiescent Power Supply Current (TTL inputs)		2.0	mA	$V_{CC} = \text{MAX}$, Outputs Open, $f_1 = 0$, $V_{IN} = V_{CC} - 0.6V^2$
I_{CCD}	Dynamic Power Supply Current ³		0.25	mA/ mHz	$V_{CC} = \text{MAX}$, One Input Toggling, 50% Duty Cycle, Outputs Open, $\overline{OE} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
I_C	Total Power Supply Current ⁵		5.3	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 5\text{MHz}$, $\overline{OE} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
			7.3	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, One Bit Toggling at $f_1 = 5\text{MHz}$, $\overline{OE} = \text{GND}$, $V_{IN} = V_{CC} - 0.6V$ or $V_{IN} = \text{GND}$
			17.8 ⁴	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling, $f_1 = 5\text{MHz}$, $\overline{OE} = \text{GND}$, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
			30.8 ⁴	mA	$V_{CC} = \text{MAX}$, $f_0 = 10\text{MHz}$, 50% Duty Cycle, Outputs Open, Eight Bits Toggling, $f_1 = 5\text{MHz}$, $\overline{OE} = \text{GND}$, $V_{IN} = V_{CC} - 0.6V$ or $V_{IN} = \text{GND}$

Notes:

- Typical values are at $V_{CC} = 3.3V$, $+25^\circ\text{C}$ ambient and maximum loading.
- Per TTL driven input ($V_{IN} = V_{CC} - 0.6V$); all other inputs at V_{CC} or GND .
- This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
- Values for these conditions are examples of the I_{CC} formula. These limits are guaranteed but not tested.
- $I_C = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$
 $I_C = I_{CCOC} + I_{CCOT} D_H N_T + I_{CCD} (f_0/2 + f_1 N_1)$
 $I_{CC} = \text{Quiescent Current with CMOS input levels}$

ΔI_{CC} = Power Supply Current for a TTL High Input
($V_{IN} = V_{CC} - 0.6V$)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)

f_0 = Clock Frequency for Register Devices (Zero for Non-Register Devices)

f_1 = Input Frequency

N_1 = Number of Inputs at f_1

All currents are in milliamps and all frequencies are in megahertz.

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OUTPUT SELECTION MUX TABLE

S_1	S_0	Output
1	1	A1
1	0	A2
0	1	B1
0	0	B2

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PIPELINE INSTRUCTION TABLE

	$I = 0$	$I = 1$	$I = 2$	$I = 3$
	$I_1 = 0, I_0 = 0$	$I_1 = 0, I_0 = 1$	$I_1 = 1, I_0 = 0$	$I_1 = 1, I_0 = 1$
'FCT39520				
'FCT39521				
	Single 4-level	Dual 2-level		Hold

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AC CHARACTERISTICS

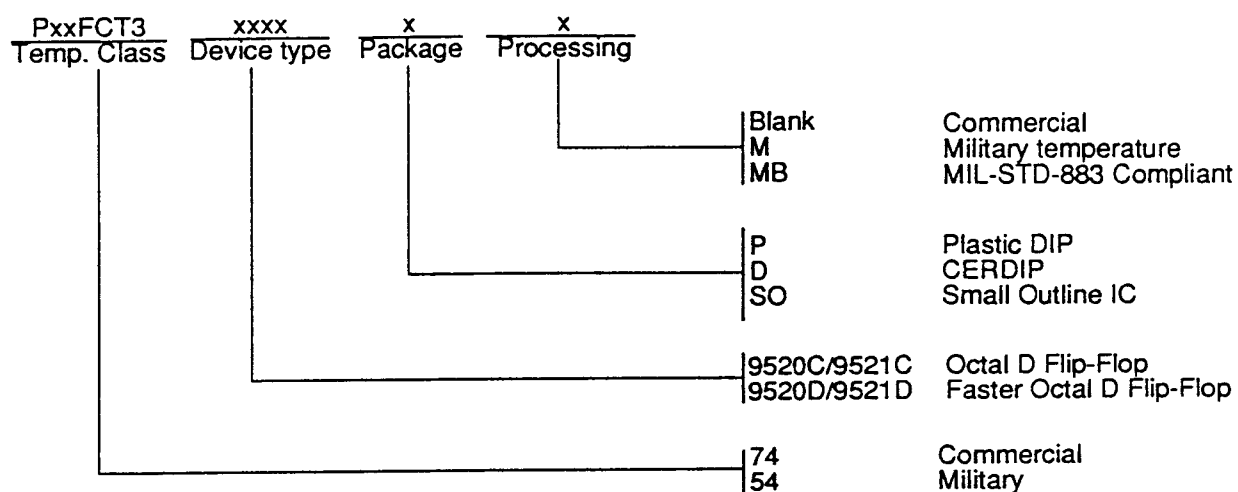
Symbol	Parameter	'FCT39520C/39521C				'FCT39520D/39521D				Units	Fig. No.
		MIL		COM'L		MIL		COM'L			
		Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.	Min. ¹	Max.		
t _{PLH} t _{PHL}	Clock to Data Output	1.5	7.0	1.5	6.0	1.5	6.0	1.5	5.1	ns ns	5
t _{PLH} t _{PHL}	S0, S1 To Data Output	1.5	7.0	1.5	6.0	1.5	6.0	1.5	5.1	ns ns	5
t _S	Setup Time Input Data to Clock	2.8	—	2.5	—	1.5	—	1.5	—	ns	9
t _H	Hold Time Input Data to Clock	2.0	—	2.0	—	1.0	—	1.0	—	ns	
t _S	Setup Time Instruction (Reg. Enable) to Clock	4.5 2.0	— —	4.0 2.0	— —	2.0 1.0	— —	2.0 1.0	— —	ns ns	9
t _H	Hold Time Instruction (Reg. Enable) to Clock	4.5 2.0	— —	4.0 2.0	— —	2.0 1.0	— —	2.0 1.0	— —	ns ns	9
t _{PHZ} t _{PLZ}	Output Disable Time	1.5	6.0	1.5	6.0	1.5	6.0	1.5	5.1	ns ns	8 7
t _{PZH} t _{PZL}	Output Enable Time	1.5	7.0	1.5	6.0	1.5	6.0	1.5	5.1	ns ns	8 7
t _{w(H)} t _{w(L)}	Clock Pulse Width, High or Low	6.0	—	5.5	—	5.0	—	4.0	—	ns ns	5 5

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Notes:

- Minimum limits are guaranteed but not tested on Propagation Delays.
AC Characteristics guaranteed with $C_L = 50\text{pF}$ as shown in Figure 1.

ORDERING INFORMATION



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